

# SN54ALS38A, SN74ALS38B QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS WITH OPEN-COLLECTOR OUTPUTS

SDAS196A – APRIL 1982 – FEBRUARY 1994

- Package Options include Plastic Small Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

## description

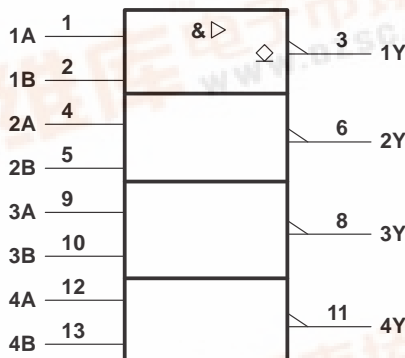
These devices contain four independent 2-input NAND buffer gates with open-collector outputs. These NAND buffers perform the Boolean functions  $Y = \overline{A \cdot B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher  $V_{OH}$  levels.

The SN54ALS38A is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to  $125^{\circ}\text{C}$ . The SN74ALS38B is characterized for operation from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$ .

FUNCTION TABLE  
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

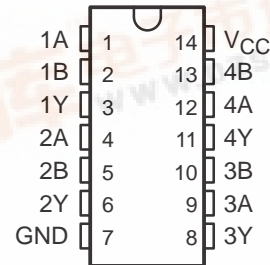
## logic symbol†



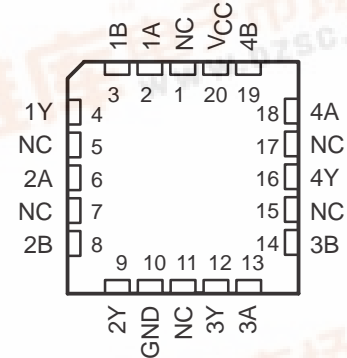
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

SN54ALS38A ... J PACKAGE  
SN74ALS38B ... D OR N PACKAGE  
(TOP VIEW)

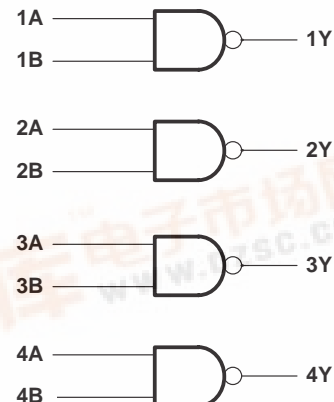


SN54ALS38A ... FK PACKAGE  
(TOP VIEW)



NC – No internal connection

## logic diagram (positive logic)



# SN54ALS38A, SN74ALS38B

## QUADRUPLE 2-INPUT POSITIVE-NAND BUFFERS

### WITH OPEN-COLLECTOR OUTPUTS

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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, $V_{CC}$	7 V
Input voltage, $V_I$	7 V
Operating free-air temperature range: SN54ALS38A	–55°C to 125°C
SN74ALS38B	0°C to 70°C
Storage temperature range	–65°C to 150°C

#### recommended operating conditions

		SN54ALS38A			SN74ALS38B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
$V_{CC}$	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
$V_{IH}$	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.7			0.8	V
$I_{OH}$	High-level output current			5.5			5.5	V
$I_{OL}$	Low-level output current			12			24	mA
$T_A$	Operating free-air temperature	–55		125	0		70	°C

#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS38A			SN74ALS38B			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
$V_{IK}$	$V_{CC} = 4.5$ V, $I_I = -18$ mA				–1.5			–1.5	V
$V_{OL}$	$V_{CC} = 4.5$ V, $I_{OL} = 12$ mA			0.25	0.4		0.25	0.4	V
	$V_{CC} = 4.5$ V, $I_{OL} = 24$ mA						0.35	0.5	
$I_{OH}$	$V_{CC} = 4.5$ V, $V_{OH} = 5.5$ V				0.1			0.1	mA
$I_I$	$V_{CC} = 5.5$ V, $V_I = 7$ V				0.1			0.1	mA
$I_{IH}$	$V_{CC} = 5.5$ V, $V_I = 2.7$ V				20			20	μA
$I_{IL}$	$V_{CC} = 5.5$ V, $V_I = 0.4$ V				–0.1			–0.1	mA
$I_{CCH}$	$V_{CC} = 5.5$ V, $V_I = 0$ V			0.86	1.6		0.86	1.6	mA
$I_{CCL}$	$V_{CC} = 5.5$ V, $V_I = 4.5$ V			4.8	7.8		4.8	7.8	mA

† All typical values are at  $V_{CC} = 5$  V,  $T_A = 25^\circ\text{C}$ .

#### switching characteristics (see Note 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 4.5 V to 5.5 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 680 Ω, T <sub>A</sub> = MIN to MAX				UNIT
			SN54ALS38A		SN74ALS38B		
			MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A or B	Y	10	59	10	33	ns
t <sub>PHL</sub>			2	18	1	12	

NOTE 1: Load circuit and voltage waveforms are shown in Section 1 of ALS/AS Logic Data Book, 1986.

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